Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/849,856	TAKIGUCHI ET AL.	
Examiner	Art Unit	
Thai Tran	2616	

	SEARCHED				
Class	Subclass	Date	Examiner		
386	1, 45, 46, 125-126	6/6/2005	Ττο		
360	46, 65	6/6/2005	TTQ		
375	229, 230	6/6/2005	TTQ		
375	232	6/6/2005	TTQ		
330	304	6/6/2005	ΤΤQ		
333	28 R	6/6/2005	TTQ		
H04N	5/76	6/6/2005	ΤQ		
H04N	9/79	6/6/2005	TTQ		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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